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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	7911
Number of Logic Elements/Cells	101261
Total RAM Bits	4939776
Number of I/O	296
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	484-BBGA
Supplier Device Package	484-FBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc6slx100t-2fgg484c

Table 3: eFUSE Programming Conditions⁽¹⁾

Symbol	Description	Min	Typ	Max	Units
V_{FS} ⁽²⁾	External voltage supply	3.2	3.3	3.4	V
I_{FS}	V_{FS} supply current	–	–	40	mA
V_{CCAUX}	Auxiliary supply voltage relative to GND	3.2	3.3	3.45	V
R_{FUSE} ⁽³⁾	External resistor from R_{FUSE} pin to GND	1129	1140	1151	Ω
V_{CCINT}	Internal supply voltage relative to GND	1.14	1.2	1.26	V
t_j	Temperature range	15	–	85	°C

Notes:

1. These specifications apply during programming of the eFUSE AES key. Programming is only supported through JTAG. The AES key is only supported in the following devices: LX75, LX75T, LX100, LX100T, LX150, and LX150T.
2. When programming eFUSE, V_{FS} must be less than or equal to V_{CCAUX} . When not programming or when eFUSE is not used, Xilinx recommends connecting V_{FS} to GND. However, V_{FS} can be between GND and 3.45 V.
3. An R_{FUSE} resistor is required when programming the eFUSE AES key. When not programming or when eFUSE is not used, Xilinx recommends connecting the R_{FUSE} pin to V_{CCAUX} or GND. However, R_{FUSE} can be unconnected.

Quiescent Current

Typical values for quiescent supply current are specified at nominal voltage, 25°C junction temperatures (T_j). Quiescent supply current is specified by speed grade for Spartan-6 devices. Xilinx recommends analyzing static power consumption using the XPOWER™ Estimator (XPE) tool (download at <http://www.xilinx.com/power>) for conditions other than those specified in Table 5.

Table 5: Typical Quiescent Supply Current

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
I_{CCINTQ}	Quiescent V_{CCINT} supply current	LX4	4.0	4.0	4.0	2.4	mA
		LX9	4.0	4.0	4.0	2.4	mA
		LX16	6.0	6.0	6.0	4.0	mA
		LX25	11.0	11.0	11.0	6.6	mA
		LX25T	11.0	11.0	11.0	N/A	mA
		LX45	15.0	15.0	15.0	9.0	mA
		LX45T	15.0	15.0	15.0	N/A	mA
		LX75	29.0	29.0	29.0	17.4	mA
		LX75T	29.0	29.0	29.0	N/A	mA
		LX100	36.0	36.0	36.0	21.6	mA
		LX100T	36.0	36.0	36.0	N/A	mA
		LX150	51.0	51.0	51.0	31.0	mA
		LX150T	51.0	51.0	51.0	N/A	mA
I_{CCOQ}	Quiescent V_{CCO} supply current	LX4	1.0	1.0	1.0	1.0	mA
		LX9	1.0	1.0	1.0	1.0	mA
		LX16	2.0	2.0	2.0	2.0	mA
		LX25	2.0	2.0	2.0	2.0	mA
		LX25T	2.0	2.0	2.0	N/A	mA
		LX45	3.0	3.0	3.0	3.0	mA
		LX45T	3.0	3.0	3.0	N/A	mA
		LX75	4.0	4.0	4.0	4.0	mA
		LX75T	4.0	4.0	4.0	N/A	mA
		LX100	5.0	5.0	5.0	5.0	mA
		LX100T	5.0	5.0	5.0	N/A	mA
		LX150	7.0	7.0	7.0	7.0	mA
		LX150T	7.0	7.0	7.0	N/A	mA

Table 5: Typical Quiescent Supply Current (Cont'd)

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
I _{CCAUXQ}	Quiescent V _{CCAUX} supply current	LX4	2.5	2.5	2.5	2.5	mA
		LX9	2.5	2.5	2.5	2.5	mA
		LX16	3.0	3.0	3.0	3.0	mA
		LX25	4.0	4.0	4.0	4.0	mA
		LX25T	4.0	4.0	4.0	N/A	mA
		LX45	5.0	5.0	5.0	5.0	mA
		LX45T	5.0	5.0	5.0	N/A	mA
		LX75	7.0	7.0	7.0	7.0	mA
		LX75T	7.0	7.0	7.0	N/A	mA
		LX100	9.0	9.0	9.0	9.0	mA
		LX100T	9.0	9.0	9.0	N/A	mA
		LX150	12.0	12.0	12.0	12.0	mA
		LX150T	12.0	12.0	12.0	N/A	mA

Notes:

- Typical values are specified at nominal voltage, 25°C junction temperatures (T_j). Industrial (I) grade devices have the same typical values as commercial (C) grade devices at 25°C, but higher values at 100°C. Use the XPE tool to calculate 100°C values. Nominal V_{CCINT} is 1.20V; use the XPE tool to calculate 1.23V values for the nominal V_{CCINT} of the extended performance range.
- Typical values are for blank configured devices with no output current loads, no active input pull-up resistors, all I/O pins are 3-state and floating.
- If differential signaling is used, more accurate quiescent current estimates can be obtained by using the XPOWER Estimator (XPE) or XPOWER Analyzer (XPA) tools.

Table 6: Power Supply Ramp Time

Symbol	Description	Speed Grade	Ramp Time	Units
V _{CCINTR}	Internal supply voltage ramp time	-3, -3N, -2	0.20 to 50.0	ms
		-1L	0.20 to 40.0	ms
V _{CCO2} ⁽¹⁾	Output drivers bank 2 supply voltage ramp time	All	0.20 to 50.0	ms
V _{CCAUXR}	Auxiliary supply voltage ramp time	All	0.20 to 50.0	ms

Notes:

- The minimum V_{CCO2} for power-on reset and configuration is 1.65V.
- Spartan-6 FPGAs require a certain amount of supply current during power-on to insure proper device initialization. The actual current consumed depends on the power-on ramp rate of the power supply. Use the XPOWER Estimator (XPE) or XPOWER Analyzer (XPA) tools to estimate current drain on these supplies. Spartan-6 devices do not have a required power-on sequence.

SelectIO™ Interface DC Input and Output Levels

Table 7: Recommended Operating Conditions for User I/Os Using Single-Ended Standards

I/O Standard	V _{CCO} for Drivers ⁽¹⁾			V _{REF} for Inputs		
	V, Min	V, Nom	V, Max	V, Min	V, Nom	V, Max
LVTTTL	3.0	3.3	3.45	V _{REF} is not used for these I/O standards		
LVC MOS33	3.0	3.3	3.45			
LVC MOS25	2.3	2.5	2.7			
LVC MOS18	1.65	1.8	1.95			
LVC MOS18_JEDEC	1.65	1.8	1.95			
LVC MOS15	1.4	1.5	1.6			
LVC MOS15_JEDEC	1.4	1.5	1.6			
LVC MOS12	1.1	1.2	1.3			
LVC MOS12_JEDEC	1.1	1.2	1.3			
PCI33_3 ⁽²⁾	3.0	3.3	3.45			
PCI66_3 ⁽²⁾	3.0	3.3	3.45			
I2C	2.7	3.0	3.45			
SMBUS	2.7	3.0	3.45			
SDIO	3.0	3.3	3.45			
MOBILE_DDR	1.7	1.8	1.9			
HSTL_I	1.4	1.5	1.6	0.68	0.75	0.9
HSTL_II	1.4	1.5	1.6	0.68	0.75	0.9
HSTL_III	1.4	1.5	1.6	–	0.9	–
HSTL_I_18	1.7	1.8	1.9	0.8	0.9	1.1
HSTL_II_18	1.7	1.8	1.9	–	0.9	–
HSTL_III_18	1.7	1.8	1.9	–	1.1	–
SSTL3_I	3.0	3.3	3.45	1.3	1.5	1.7
SSTL3_II	3.0	3.3	3.45	1.3	1.5	1.7
SSTL2_I	2.3	2.5	2.7	1.13	1.25	1.38
SSTL2_II	2.3	2.5	2.7	1.13	1.25	1.38
SSTL18_I	1.7	1.8	1.9	0.833	0.9	0.969
SSTL18_II	1.7	1.8	1.9	0.833	0.9	0.969
SSTL15_II	1.425	1.5	1.575	0.69	0.75	0.81

Notes:

1. V_{CCO} range required when using I/O standard for an output. Also required for MOBILE_DDR, PCI33_3, LVC MOS18_JEDEC, LVC MOS15_JEDEC, and LVC MOS12_JEDEC inputs, and for LVC MOS25 inputs when V_{CCAUX} = 3.3V.
2. For PCI systems, the transmitter and receiver should have common supplies for V_{CCO}.

Table 8: Recommended Operating Conditions for User I/Os Using Differential Signal Standards

I/O Standard	V _{CCO} for Drivers		
	V, Min	V, Nom	V, Max
LVDS_33	3.0	3.3	3.45
LVDS_25	2.25	2.5	2.75
BLVDS_25	2.25	2.5	2.75
MINI_LVDS_33	3.0	3.3	3.45
MINI_LVDS_25	2.25	2.5	2.75
LVPECL_33 ⁽¹⁾	N/A—Inputs Only		
LVPECL_25	N/A—Inputs Only		
RSDS_33	3.0	3.3	3.45
RSDS_25	2.25	2.5	2.75
TMDS_33 ⁽¹⁾	3.14	3.3	3.45
PPDS_33	3.0	3.3	3.45
PPDS_25	2.25	2.5	2.75
DISPLAY_PORT	2.3	2.5	2.7
DIFF_MOBILE_DDR	1.7	1.8	1.9
DIFF_HSTL_I	1.4	1.5	1.6
DIFF_HSTL_II	1.4	1.5	1.6
DIFF_HSTL_III	1.4	1.5	1.6
DIFF_HSTL_I_18	1.7	1.8	1.9
DIFF_HSTL_II_18	1.7	1.8	1.9
DIFF_HSTL_III_18	1.7	1.8	1.9
DIFF_SSTL3_I	3.0	3.3	3.45
DIFF_SSTL3_II	3.0	3.3	3.45
DIFF_SSTL2_I	2.3	2.5	2.7
DIFF_SSTL2_II	2.3	2.5	2.7
DIFF_SSTL18_I	1.7	1.8	1.9
DIFF_SSTL18_II	1.7	1.8	1.9
DIFF_SSTL15_II	1.425	1.5	1.575

Notes:

1. LVPECL_33 and TMDS_33 inputs require V_{CCAUX} = 3.3V nominal.

eFUSE Read Endurance

Table 11 lists the minimum guaranteed number of read cycle operations for Device DNA and for the AES eFUSE key. For more information, see [UG380: Spartan-6 FPGA Configuration User Guide](#).

Table 11: eFUSE Read Endurance

Symbol	Description	Speed Grade				Units (Min)
		-3	-3N	-2	-1L	
DNA_CYCLES	Number of DNA_PORT READ operations or JTAG ISC_DNA read command operations. Unaffected by SHIFT operations.	30,000,000				Read Cycles
AES_CYCLES	Number of JTAG FUSE_KEY or FUSE_CNTL read command operations. Unaffected by SHIFT operations.	30,000,000				Read Cycles

GTP Transceiver Specifications

GTP transceivers are available in the Spartan-6 LXT devices. See [DS160: Spartan-6 Family Overview](#) for more information.

GTP Transceiver DC Characteristics

Table 12: Absolute Maximum Ratings for GTP Transceivers⁽¹⁾

Symbol	Description	Min	Max	Units
MGTAVCC	Analog supply voltage for the GTP transmitter and receiver circuits relative to GND	-0.5	1.32	V
MGTAVTTTX	Analog supply voltage for the GTP transmitter termination circuit relative to GND	-0.5	1.32	V
MGTAVTTRX	Analog supply voltage for the GTP receiver termination circuit relative to GND	-0.5	1.32	V
MGTAVCCPLL	Analog supply voltage for the GTP transmitter and receiver PLL circuits relative to GND	-0.5	1.32	V
MGTAVTTRCAL	Analog supply voltage for the resistor calibration circuit of the GTP transceiver bank (top or bottom)	-0.5	1.32	V
V _{IN}	Receiver (RXP/RXN) and Transmitter (TXP/TXN) absolute input voltage	-0.5	1.32	V
V _{MGTREFCLK}	Reference clock absolute input voltage	-0.5	1.32	V

Notes:

- Stresses beyond those listed under Absolute Maximum Ratings might cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time might affect device reliability.

Table 13: Recommended Operating Conditions for GTP Transceivers⁽¹⁾⁽²⁾⁽³⁾

Symbol	Description	Min	Typ	Max	Units
MGTAVCC	Analog supply voltage for the GTP transmitter and receiver circuits relative to GND	1.14	1.20	1.26	V
MGTAVTTTX	Analog supply voltage for the GTP transmitter termination circuit relative to GND	1.14	1.20	1.26	V
MGTAVTTRX	Analog supply voltage for the GTP receiver termination circuit relative to GND	1.14	1.20	1.26	V
MGTAVCCPLL	Analog supply voltage for the GTP transmitter and receiver PLL circuits relative to GND	1.14	1.20	1.26	V
MGTAVTTRCAL	Analog supply voltage for the resistor calibration circuit of the GTP transceiver bank (top or bottom)	1.14	1.20	1.26	V

Notes:

- Each voltage listed requires the filter circuit described in [UG386: Spartan-6 FPGA GTP Transceivers User Guide](#).
- Voltages are specified for the temperature range of T_j = -40°C to +125°C.
- The voltage level of MGTAVCCPLL must not exceed the voltage level of MGTAVCC +10mV. The voltage level of MGTAVCC must not exceed the voltage level of MGTAVCCPLL.

Table 14: GTP Transceiver Current Supply (per Lane)

Symbol	Description	Typ ⁽¹⁾	Max	Units
I _{MGTAVCC}	GTP transceiver internal analog supply current	40.4	Note 2	mA
I _{MGTAVTTTX}	GTP transmitter termination supply current	27.4		mA
I _{MGTAVTTRX}	GTP receiver termination supply current	13.6		mA
I _{MGTAVCCPLL}	GTP transmitter and receiver PLL supply current	28.7		mA
R _{MGTRREF}	Precision reference resistor for internal calibration termination	50.0 ± 1% tolerance		Ω

Notes:

- Typical values are specified at nominal voltage, 25°C, with a 2.5 Gb/s line rate, with a shared PLL use mode.
- Values for currents of other transceiver configurations and conditions can be obtained by using the XPOWER Estimator (XPE) or XPOWER Analyzer (XPA) tools.

Table 15: GTP Transceiver Quiescent Supply Current (per Lane)⁽¹⁾⁽²⁾⁽³⁾⁽⁴⁾

Symbol	Description	Typ ⁽⁵⁾	Max	Units
I _{MGTAVCCQ}	Quiescent MGTAVCC supply current	1.7	Note 2	mA
I _{MGTAVTTTXQ}	Quiescent MGTAVTTTX supply current	0.1		mA
I _{MGTAVTTRXQ}	Quiescent MGTAVTTRX supply current	1.2		mA
I _{MGTAVCCPLLQ}	Quiescent MGTAVCCPLL supply current	1.0		mA

Notes:

- Device powered and unconfigured.
- Currents for conditions other than values specified in this table can be obtained by using the XPOWER Estimator (XPE) or XPOWER Analyzer (XPA) tools.
- GTP transceiver quiescent supply current for an entire device can be calculated by multiplying the values in this table by the number of available GTP transceivers.
- Does not include power-up MGTAVTTRCAL supply current during device configuration.
- Typical values are specified at nominal voltage, 25°C.

Table 23: GTP Transceiver Receiver Switching Characteristics

Symbol	Description		Min	Typ	Max	Units	
T _{RXELECIDLE}	Time for RXELECIDLE to respond to loss or restoration of data		–	75	–	ns	
R _{XOOBVDPP}	OOB detect threshold peak-to-peak		60	–	150	mV	
R _{XSST}	Receiver spread-spectrum tracking ⁽¹⁾	Modulated @ 33 KHz	–5000	–	0	ppm	
R _{XR_L}	Run length (CID)	Internal AC capacitor bypassed	–	–	150	UI	
R _{XPMTOL}	Data/REFCLK PPM offset tolerance	CDR 2 nd -order loop disabled	–200	–	200	ppm	
		CDR 2 nd -order loop enabled	PLL_RXDIVSEL_OUT = 1	–2000	–	2000	ppm
			PLL_RXDIVSEL_OUT = 2	–2000	–	2000	ppm
			PLL_RXDIVSEL_OUT = 4	–1000	–	1000	ppm
SJ Jitter Tolerance ⁽²⁾							
JT_SJ _{3.125}	Sinusoidal Jitter ⁽³⁾	3.125 Gb/s	0.4	–	–	UI	
JT_SJ _{2.5}	Sinusoidal Jitter ⁽³⁾	2.5 Gb/s	0.4	–	–	UI	
JT_SJ _{1.62}	Sinusoidal Jitter ⁽³⁾	1.62 Gb/s	0.5	–	–	UI	
JT_SJ _{1.25}	Sinusoidal Jitter ⁽³⁾	1.25 Gb/s	0.5	–	–	UI	
JT_SJ ₆₁₄	Sinusoidal Jitter ⁽³⁾	614 Mb/s	0.5	–	–	UI	
SJ Jitter Tolerance with Stressed Eye ⁽²⁾⁽⁵⁾							
JT_TJSE _{3.125}	Total Jitter with stressed eye ⁽⁴⁾	3.125 Gb/s	0.65	–	–	UI	
JT_SJSE _{3.125}	Sinusoidal Jitter with stressed eye	3.125 Gb/s	0.1	–	–	UI	
JT_TJSE _{2.7}	Total Jitter with stressed eye ⁽⁴⁾	2.7 Gb/s	0.65	–	–	UI	
JT_SJSE _{2.7}	Sinusoidal Jitter with stressed eye	2.7 Gb/s	0.1	–	–	UI	

Notes:

- Using PLL_RXDIVSEL_OUT = 1, 2, and 4.
- All jitter values are based on a Bit Error Ratio of 1e⁻¹².
- Using 80 MHz sinusoidal jitter only in the absence of deterministic and random jitter.
- Composed of 0.37 UI DJ in the form of ISI and 0.18 UI RJ.
- Measured using PRBS7 data pattern.

Endpoint Block for PCI Express Designs Switching Characteristics

The Endpoint block for PCI Express is available in the Spartan-6 LXT devices. Consult the [Spartan-6 FPGA Integrated Endpoint Block for PCI Express](#) for further information.

Table 24: Maximum Performance for PCI Express Designs

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
F _{PCIEUSER}	User clock maximum frequency	62.5	62.5	62.5	N/A	MHz

Performance Characteristics

This section provides the performance characteristics of some common functions and designs implemented in Spartan-6 devices. The numbers reported here are worst-case values; they have all been fully characterized. These values are subject to the same guidelines as the [Switching Characteristics, page 19](#).

Table 25: Interface Performances

Description	I/O Resource	Clock Buffer	Data Width	Speed Grade				Units
				-3	-3N	-2	-1L	
Networking Applications ⁽¹⁾								
SDR LVDS transmitter or receiver	IOB SDR register	BUFG	–	400	400	375	250	Mb/s
DDR LVDS transmitter or receiver	ODDR2/IDDR2 register	2 BUFPGs	–	800	800	750	500	Mb/s
SDR LVDS transmitter	OSERDES2	BUFPLL	2	500	500	500	250	Mb/s
			3	750	750	750	375	Mb/s
			4-8	1080	1050	950	500	Mb/s
DDR LVDS transmitter	OSERDES2	2 BUFIO2s	2	500	500	500	250	Mb/s
			3	750	750	750	375	Mb/s
			4-8	1080	1050	950	500	Mb/s
SDR LVDS receiver	ISERDES2 in RETIMED mode	BUFPLL	2	500	500	500	—	Mb/s
			3	750	750	750	—	Mb/s
			4-8	1080	1050	950	—	Mb/s
DDR LVDS receiver	ISERDES2 in RETIMED mode	2 BUFIO2s	2	500	500	500	—	Mb/s
			3	750	750	750	—	Mb/s
			4-8	1080	1050	950	—	Mb/s
Memory Interfaces (Implemented using the Spartan-6 FPGA Memory Controller Block) ⁽²⁾								
Standard Performance (Standard V _{CCINT})								
DDR				400	Note 4	400	350	Mb/s
DDR2				667	Note 4	625	400	Mb/s
DDR3				800	Note 4	667	—	Mb/s
LPDDR (Mobile_DDR)				400	Note 4	400	350	Mb/s
Extended Performance (Requires Extended Performance V _{CCINT}) ⁽³⁾								
DDR2				800	Note 4	667	—	Mb/s

Notes:

1. Refer to [XAPP1064](#), *Source-Synchronous Serialization and Deserialization (up to 1050 Mb/s)* and [UG381](#), *Spartan-6 FPGA SelectIO Resources User Guide*.
2. Refer to [UG388](#), *Spartan-6 FPGA Memory Controller User Guide*.
3. Extended Memory Controller block performance for DDR2 can be achieved using the extended performance V_{CCINT} range from [Table 2](#).
4. The LX4 device, all devices in the TQG144 and CPG196 packages, and the -3N speed grade do not support a Memory Controller Block.

Production Silicon and ISE Software Status

In some cases, a particular family member (and speed grade) is released to production before a speed specification is released with the correct label (Advance, Preliminary, Production). Any labeling discrepancies are corrected in subsequent speed specification releases. [Table 27](#) lists the production released Spartan-6 family member, speed grade, and the minimum corresponding supported speed specification version and ISE® software revisions. The ISE software and speed specifications listed are the minimum releases required for production. All subsequent releases of software and speed specifications are valid.

Table 27: Spartan-6 Device Production Software and Speed Specification Release⁽¹⁾

Device	Speed Grade Designations ⁽²⁾			
	-3 ⁽³⁾	-3N	-2 ⁽⁴⁾	-1L
XC6SLX4	ISE 12.4 v1.15	N/A	ISE 12.3 v1.12 ⁽⁵⁾	ISE 13.2 v1.07
XC6SLX9	ISE 12.4 v1.15	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.3 v1.12 ⁽⁵⁾	ISE 13.2 v1.07
XC6SLX16	ISE 12.1 v1.08	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 11.5 v1.06	ISE 13.2 v1.07
XC6SLX25	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.2 v1.07
XC6SLX25T	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.2 v1.11 ⁽⁶⁾	N/A
XC6SLX45	ISE 12.1 v1.08	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 11.5 v1.07	ISE 13.1 v1.06
XC6SLX45T	ISE 12.1 v1.08	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.1 v1.08	N/A
XC6SLX75	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.2 v1.07
XC6SLX75T	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.2 v1.11 ⁽⁶⁾	N/A
XC6SLX100	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 v1.06
XC6SLX100T	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.2 v1.11 ⁽⁶⁾	N/A
XC6SLX150	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 v1.06
XC6SLX150T	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.2 v1.11 ⁽⁶⁾	N/A
XA6SLX4	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX9	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX16	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX25	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX25T	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX45	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX45T	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX75	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX75T	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX100	N/A	N/A	ISE 13.3 v1.20	N/A

Table 28: IOB Switching Characteristics for the Commercial (XC) Spartan-6 Devices (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-3N	-2	-1L ⁽¹⁾	-3	-3N	-2	-1L ⁽¹⁾	-3	-3N	-2	-1L ⁽¹⁾	
PPDS_33	1.17	1.29	1.42	1.68	1.57	1.71	1.91	2.43	3000	3000	3000	3000	ns
PPDS_25	1.01	1.13	1.26	1.56	1.68	1.82	2.02	2.47	3000	3000	3000	3000	ns
PCI33_3	1.07	1.19	1.32	1.57 ⁽²⁾	3.51	3.65	3.85	4.38 ⁽²⁾	3.51	3.65	3.85	4.38 ⁽¹⁾	ns
PCI66_3	1.07	1.19	1.32	1.57 ⁽²⁾	3.53	3.67	3.87	4.39 ⁽²⁾	3.53	3.67	3.87	4.39 ⁽¹⁾	ns
DISPLAY_PORT	1.02	1.14	1.27	1.56	3.15	3.29	3.49	4.08	3.15	3.29	3.49	4.08	ns
I2C	1.33	1.45	1.58	1.82	11.56	11.70	11.90	12.52	11.56	11.70	11.90	12.52	ns
SMBUS	1.33	1.45	1.58	1.82	11.56	11.70	11.90	12.52	11.56	11.70	11.90	12.52	ns
SDIO	1.36	1.48	1.61	1.84	2.64	2.78	2.98	3.60	2.64	2.78	2.98	3.60	ns
MOBILE_DDR	0.94	1.06	1.19	1.43	2.35	2.49	2.69	3.31	2.35	2.49	2.69	3.31	ns
HSTL_I	0.90	1.02	1.15	1.39	1.66	1.80	2.00	2.62	1.66	1.80	2.00	2.62	ns
HSTL_II	0.91	1.03	1.16	1.40	1.72	1.86	2.06	2.68	1.72	1.86	2.06	2.68	ns
HSTL_III	0.95	1.07	1.20	1.44	1.67	1.81	2.01	2.61	1.67	1.81	2.01	2.61	ns
HSTL_I_18	0.94	1.06	1.19	1.43	1.77	1.91	2.11	2.73	1.77	1.91	2.11	2.73	ns
HSTL_II_18	0.94	1.06	1.19	1.43	1.85	1.99	2.19	2.81	1.85	1.99	2.19	2.81	ns
HSTL_III_18	0.99	1.11	1.24	1.47	1.79	1.93	2.13	2.72	1.79	1.93	2.13	2.72	ns
SSTL3_I	1.58	1.70	1.83	2.16	1.83	1.97	2.17	2.72	1.83	1.97	2.17	2.72	ns
SSTL3_II	1.58	1.70	1.83	2.16	2.01	2.15	2.35	2.94	2.01	2.15	2.35	2.94	ns
SSTL2_I	1.30	1.42	1.55	1.87	1.77	1.91	2.11	2.69	1.77	1.91	2.11	2.69	ns
SSTL2_II	1.30	1.42	1.55	1.88	1.86	2.00	2.20	2.82	1.86	2.00	2.20	2.82	ns
SSTL18_I	0.92	1.04	1.17	1.41	1.63	1.77	1.97	2.59	1.63	1.77	1.97	2.59	ns
SSTL18_II	0.92	1.04	1.17	1.41	1.66	1.80	2.00	2.62	1.66	1.80	2.00	2.62	ns
SSTL15_II	0.92	1.04	1.17	1.41	1.67	1.81	2.01	2.63	1.67	1.81	2.01	2.63	ns
DIFF_HSTL_I	0.94	1.06	1.19	1.46	1.77	1.91	2.11	2.62	1.77	1.91	2.11	2.62	ns
DIFF_HSTL_II	0.93	1.05	1.18	1.45	1.72	1.86	2.06	2.54	1.72	1.86	2.06	2.54	ns
DIFF_HSTL_III	0.93	1.05	1.18	1.46	1.69	1.83	2.03	2.53	1.69	1.83	2.03	2.53	ns
DIFF_HSTL_I_18	0.97	1.09	1.22	1.50	1.79	1.93	2.13	2.63	1.79	1.93	2.13	2.63	ns
DIFF_HSTL_II_18	0.97	1.09	1.22	1.49	1.69	1.83	2.03	2.51	1.69	1.83	2.03	2.51	ns
DIFF_HSTL_III_18	0.97	1.09	1.22	1.50	1.69	1.83	2.03	2.53	1.69	1.83	2.03	2.53	ns
DIFF_SSTL3_I	1.18	1.30	1.43	1.68	1.81	1.95	2.15	2.64	1.81	1.95	2.15	2.64	ns
DIFF_SSTL3_II	1.19	1.31	1.44	1.68	1.80	1.94	2.14	2.63	1.80	1.94	2.14	2.63	ns
DIFF_SSTL2_I	1.02	1.14	1.27	1.57	1.80	1.94	2.14	2.62	1.80	1.94	2.14	2.62	ns
DIFF_SSTL2_II	1.02	1.14	1.27	1.57	1.76	1.90	2.10	2.57	1.76	1.90	2.10	2.57	ns
DIFF_SSTL18_I	0.97	1.09	1.22	1.51	1.72	1.86	2.06	2.56	1.72	1.86	2.06	2.56	ns
DIFF_SSTL18_II	0.98	1.10	1.23	1.50	1.68	1.82	2.02	2.52	1.68	1.82	2.02	2.52	ns
DIFF_SSTL15_II	0.94	1.06	1.19	1.46	1.67	1.81	2.01	2.50	1.67	1.81	2.01	2.50	ns
DIFF_MOBILE_DDR	0.97	1.09	1.22	1.51	1.75	1.89	2.09	2.57	1.75	1.89	2.09	2.57	ns

Table 28: IOB Switching Characteristics for the Commercial (XC) Spartan-6 Devices (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-3N	-2	-1L ⁽¹⁾	-3	-3N	-2	-1L ⁽¹⁾	-3	-3N	-2	-1L ⁽¹⁾	
LVC MOS15, Slow, 8 mA	0.98	1.10	1.23	1.79	2.30	2.44	2.64	3.25	2.30	2.44	2.64	3.25	ns
LVC MOS15, Slow, 12 mA	0.98	1.10	1.23	1.79	2.03	2.17	2.37	2.99	2.03	2.17	2.37	2.99	ns
LVC MOS15, Slow, 16 mA	0.98	1.10	1.23	1.79	2.01	2.15	2.35	2.97	2.01	2.15	2.35	2.97	ns
LVC MOS15, Fast, 2 mA	0.98	1.10	1.23	1.79	3.29	3.43	3.63	4.24	3.29	3.43	3.63	4.24	ns
LVC MOS15, Fast, 4 mA	0.98	1.10	1.23	1.79	2.27	2.41	2.61	3.22	2.27	2.41	2.61	3.22	ns
LVC MOS15, Fast, 6 mA	0.98	1.10	1.23	1.79	1.78	1.92	2.12	2.74	1.78	1.92	2.12	2.74	ns
LVC MOS15, Fast, 8 mA	0.98	1.10	1.23	1.79	1.73	1.87	2.07	2.69	1.73	1.87	2.07	2.69	ns
LVC MOS15, Fast, 12 mA	0.98	1.10	1.23	1.79	1.73	1.87	2.07	2.64	1.73	1.87	2.07	2.64	ns
LVC MOS15, Fast, 16 mA	0.98	1.10	1.23	1.79	1.73	1.87	2.07	2.64	1.73	1.87	2.07	2.64	ns
LVC MOS15_JEDEC, QUIETIO, 2 mA	1.03	1.15	1.28	1.49	5.49	5.63	5.83	6.37	5.49	5.63	5.83	6.37	ns
LVC MOS15_JEDEC, QUIETIO, 4 mA	1.03	1.15	1.28	1.49	4.61	4.75	4.95	5.51	4.61	4.75	4.95	5.51	ns
LVC MOS15_JEDEC, QUIETIO, 6 mA	1.03	1.15	1.28	1.49	4.07	4.21	4.41	4.97	4.07	4.21	4.41	4.97	ns
LVC MOS15_JEDEC, QUIETIO, 8 mA	1.03	1.15	1.28	1.49	3.92	4.06	4.26	4.81	3.92	4.06	4.26	4.81	ns
LVC MOS15_JEDEC, QUIETIO, 12 mA	1.03	1.15	1.28	1.49	3.54	3.68	3.88	4.51	3.54	3.68	3.88	4.51	ns
LVC MOS15_JEDEC, QUIETIO, 16 mA	1.03	1.15	1.28	1.49	3.33	3.47	3.67	4.31	3.33	3.47	3.67	4.31	ns
LVC MOS15_JEDEC, Slow, 2 mA	1.03	1.15	1.28	1.49	4.18	4.32	4.52	5.13	4.18	4.32	4.52	5.13	ns
LVC MOS15_JEDEC, Slow, 4 mA	1.03	1.15	1.28	1.49	3.42	3.56	3.76	4.35	3.42	3.56	3.76	4.35	ns
LVC MOS15_JEDEC, Slow, 6 mA	1.03	1.15	1.28	1.49	2.29	2.43	2.63	3.25	2.29	2.43	2.63	3.25	ns
LVC MOS15_JEDEC, Slow, 8 mA	1.03	1.15	1.28	1.49	2.30	2.44	2.64	3.26	2.30	2.44	2.64	3.26	ns
LVC MOS15_JEDEC, Slow, 12 mA	1.03	1.15	1.28	1.49	2.01	2.15	2.35	2.97	2.01	2.15	2.35	2.97	ns
LVC MOS15_JEDEC, Slow, 16 mA	1.03	1.15	1.28	1.49	2.01	2.15	2.35	2.97	2.01	2.15	2.35	2.97	ns
LVC MOS15_JEDEC, Fast, 2 mA	1.03	1.15	1.28	1.49	3.28	3.42	3.62	4.22	3.28	3.42	3.62	4.22	ns
LVC MOS15_JEDEC, Fast, 4 mA	1.03	1.15	1.28	1.49	2.27	2.41	2.61	3.23	2.27	2.41	2.61	3.23	ns
LVC MOS15_JEDEC, Fast, 6 mA	1.03	1.15	1.28	1.49	1.78	1.92	2.12	2.74	1.78	1.92	2.12	2.74	ns
LVC MOS15_JEDEC, Fast, 8 mA	1.03	1.15	1.28	1.49	1.73	1.87	2.07	2.69	1.73	1.87	2.07	2.69	ns
LVC MOS15_JEDEC, Fast, 12 mA	1.03	1.15	1.28	1.49	1.73	1.87	2.07	2.63	1.73	1.87	2.07	2.63	ns
LVC MOS15_JEDEC, Fast, 16 mA	1.03	1.15	1.28	1.49	1.73	1.87	2.07	2.63	1.73	1.87	2.07	2.63	ns
LVC MOS12, QUIETIO, 2 mA	0.91	1.03	1.16	1.51	6.40	6.54	6.74	7.30	6.40	6.54	6.74	7.30	ns
LVC MOS12, QUIETIO, 4 mA	0.91	1.03	1.16	1.51	4.98	5.12	5.32	5.90	4.98	5.12	5.32	5.90	ns
LVC MOS12, QUIETIO, 6 mA	0.91	1.03	1.16	1.51	4.65	4.79	4.99	5.55	4.65	4.79	4.99	5.55	ns
LVC MOS12, QUIETIO, 8 mA	0.91	1.03	1.16	1.51	4.23	4.37	4.57	5.21	4.23	4.37	4.57	5.21	ns
LVC MOS12, QUIETIO, 12 mA	0.91	1.03	1.16	1.51	3.98	4.12	4.32	4.94	3.98	4.12	4.32	4.94	ns
LVC MOS12, Slow, 2 mA	0.91	1.03	1.16	1.51	4.98	5.12	5.32	5.91	4.98	5.12	5.32	5.91	ns
LVC MOS12, Slow, 4 mA	0.91	1.03	1.16	1.51	2.84	2.98	3.18	3.81	2.84	2.98	3.18	3.81	ns
LVC MOS12, Slow, 6 mA	0.91	1.03	1.16	1.51	2.77	2.91	3.11	3.72	2.77	2.91	3.11	3.72	ns
LVC MOS12, Slow, 8 mA	0.91	1.03	1.16	1.51	2.34	2.48	2.68	3.31	2.34	2.48	2.68	3.31	ns
LVC MOS12, Slow, 12 mA	0.91	1.03	1.16	1.51	2.08	2.22	2.42	3.06	2.08	2.22	2.42	3.06	ns

Table 54: Switching Characteristics for the Delay-Locked Loop (DLL)⁽¹⁾

Symbol	Description	Speed Grade								Units
		-3		-3N		-2		-1L		
		Min	Max	Min	Max	Min	Max	Min	Max	
Output Frequency Ranges										
CLKOUT_FREQ_CLK0	Frequency for the CLK0 and CLK180 outputs.	5	280	5	280	5	250	5	175	MHz
CLKOUT_FREQ_CLK90	Frequency for the CLK90 and CLK270 outputs.	5	200	5	200	5	200	5	175	MHz
CLKOUT_FREQ_2X	Frequency for the CLK2X and CLK2X180 outputs.	10	375	10	375	10	334	10	250	MHz
CLKOUT_FREQ_DV	Frequency for the CLKDV output.	0.3125	186	0.3125	186	0.3125	166	0.3125	88.6	MHz
Output Clock Jitter ⁽²⁾⁽³⁾⁽⁴⁾										
CLKOUT_PER_JITT_0	Period jitter at the CLK0 output.	–	±100	–	±100	–	±100	–	±100	ps
CLKOUT_PER_JITT_90	Period jitter at the CLK90 output.	–	±150	–	±150	–	±150	–	±150	ps
CLKOUT_PER_JITT_180	Period jitter at the CLK180 output.	–	±150	–	±150	–	±150	–	±150	ps
CLKOUT_PER_JITT_270	Period jitter at the CLK270 output.	–	±150	–	±150	–	±150	–	±150	ps
CLKOUT_PER_JITT_2X	Period jitter at the CLK2X and CLK2X180 outputs.	Maximum = ±[0.5% of CLKIN period + 100]								ps
CLKOUT_PER_JITT_DV1	Period jitter at the CLKDV output when performing integer division.	–	±150	–	±150	–	±150	–	±150	ps
CLKOUT_PER_JITT_DV2	Period jitter at the CLKDV output when performing non-integer division.	Maximum = ±[0.5% of CLKIN period + 100]								ps
Duty Cycle ⁽⁴⁾										
CLKOUT_DUTY_CYCLE_DLL	Duty cycle variation for the CLK0, CLK90, CLK180, CLK270, CLK2X, CLK2X180, and CLKDV outputs, including the BUFGMUX and clock tree duty-cycle distortion.	Typical = ±[1% of CLKIN period + 350]								ps
Phase Alignment ⁽⁴⁾										
CLKIN_CLKFB_PHASE	Phase offset between the CLKIN and CLKFB inputs (CLK_FEEDBACK = 1X).	–	±150	–	±150	–	±150	–	±250	ps
	Phase offset between the CLKIN and CLKFB inputs (CLK_FEEDBACK = 2X). ⁽⁶⁾	–	±250	–	±250	–	±250	–	±350	
CLKOUT_PHASE_DLL	Phase offset between DLL outputs for CLK0 to CLK2X (not CLK2X180).	Maximum = ±[1% of CLKIN period + 100]								ps
	Phase offset between DLL outputs for all others.	Maximum = ±[1% of CLKIN period + 150]						Maximum = ±[1% of CLKIN period + 200]		ps

Table 57: Switching Characteristics for the Digital Frequency Synthesizer DFS (DCM_CLKGEN)⁽¹⁾

Symbol	Description	Speed Grade								Units
		-3		-3N		-2		-1L		
		Min	Max	Min	Max	Min	Max	Min	Max	
Output Frequency Ranges (DCM_CLKGEN)										
CLKOUT_FREQ_FX	Frequency for the CLKFX and CLKFX180 outputs	5	375	5	375	5	333	5	200	MHz
CLKOUT_FREQ_FXDV	Frequency for the CLKFXDV output	0.15625	187.5	0.15625	187.5	0.15625	166.5	0.15625	100	MHz
Output Clock Jitter ⁽²⁾⁽³⁾										
CLKOUT_PER_JITT_FX	Period jitter at the CLKFX and CLKFX180 outputs.	Typical = ±[0.2% of CLKFX period + 100]								ps
CLKOUT_PER_JITT_FXDV	Period jitter at the CLKFXDV output.	Typical = ±[0.2% of CLKFX period + 100]								ps
CLKFX_FREEZE_VAR	CLKFX period change in free running oscillator mode at the same temperature. FCLKFX > 50 MHz	Maximum = ±3% of CLKFX period								ps
	CLKFX period change in free running oscillator mode at the same temperature. FCLKFX < 50 MHz	Maximum = ±5% of CLKFX period								ps
CLKFX_FREEZE_TEMP_SLOPE	CLKFX period will change in free_oscillator mode over temperature. Add to CLKFX_FREEZE_VAR to determine total CLKFX period change. Percentage change for CLKFX period over 1°C.	Maximum = 0.1								%/°C
Duty Cycle ⁽⁴⁾⁽⁵⁾										
CLKOUT_DUTY_CYCLE_FX	Duty cycle precision for the CLKFX and CLKFX180 outputs, including the BUFGMUX and clock tree duty-cycle distortion	Maximum = ±[1% of CLKFX period + 350]								ps
CLKOUT_DUTY_CYCLE_FXDV	Duty cycle precision for the CLKFXDV outputs, including the BUFGMUX and clock tree duty-cycle distortion	Maximum = ±[1% of CLKFX period + 350]								ps
Lock Time										
LOCK_FX ⁽²⁾	The time from deassertion at the DCM's Reset input to the rising transition at its LOCKED output. The DFS asserts LOCKED when the CLKFX, CLKFX180, and CLKFXDV signals are valid. Lock time requires CLKFX_DIVIDE < F _{IN} /(0.50 MHz) when: F _{CLKIN} < 50 MHz	—	50	—	50	—	50	—	50	ms
	when: F _{CLKIN} > 50 MHz	—	5	—	5	—	5	—	5	ms

Spartan-6 Device Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. The representative values for typical pin locations and normal clock loading are listed in Table 63 through Table 69. Values are expressed in nanoseconds unless otherwise noted.

Table 63: Global Clock Input to Output Delay Without DCM or PLL

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
LVCMOS25 Global Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, <i>without</i> DCM or PLL							
T _{ICKOF}	Global Clock and OUTFF <i>without</i> DCM or PLL	XC6SLX4	6.12	N/A	7.68	9.41	ns
		XC6SLX9	6.12	6.51	7.68	9.41	ns
		XC6SLX16	5.98	6.42	7.48	9.10	ns
		XC6SLX25	6.20	6.69	7.84	9.44	ns
		XC6SLX25T	6.20	6.69	7.84	N/A	ns
		XC6SLX45	6.37	6.88	8.10	9.61	ns
		XC6SLX45T	6.37	6.88	8.10	N/A	ns
		XC6SLX75	6.39	6.99	8.16	10.18	ns
		XC6SLX75T	6.39	6.99	8.16	N/A	ns
		XC6SLX100	6.59	7.18	8.41	10.31	ns
		XC6SLX100T	6.59	7.18	8.41	N/A	ns
		XC6SLX150	6.98	7.68	8.80	10.62	ns
		XC6SLX150T	6.98	7.68	8.80	N/A	ns
		XA6SLX4	6.44	N/A	7.68	N/A	ns
		XA6SLX9	6.44	N/A	7.68	N/A	ns
		XA6SLX16	6.30	N/A	7.48	N/A	ns
		XA6SLX25	6.52	N/A	7.84	N/A	ns
		XA6SLX25T	6.52	N/A	7.84	N/A	ns
		XA6SLX45	6.69	N/A	8.12	N/A	ns
		XA6SLX45T	6.69	N/A	8.12	N/A	ns
		XA6SLX75	6.89	N/A	8.16	N/A	ns
		XA6SLX75T	6.89	N/A	8.16	N/A	ns
		XA6SLX100	N/A	N/A	8.36	N/A	ns
		XQ6SLX75	N/A	N/A	8.16	10.18	ns
		XQ6SLX75T	6.89	N/A	8.16	N/A	ns
		XQ6SLX150	N/A	N/A	8.80	10.62	ns
		XQ6SLX150T	7.61	N/A	8.80	N/A	ns

Notes:

- Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.

Table 68: Global Clock Input to Output Delay With DCM and PLL in System-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
LVCMOS25 Global Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, <i>with</i> DCM in System-Synchronous Mode and PLL in DCM2PLL Mode.							
T _{ICKOFDCM_PLL}	Global Clock and OUTFF with DCM and PLL	XC6SLX4	4.78	N/A	6.32	7.09	ns
		XC6SLX9	4.78	5.24	6.32	7.09	ns
		XC6SLX16	4.70	5.12	5.94	6.63	ns
		XC6SLX25	4.70	5.09	5.92	7.30	ns
		XC6SLX25T	4.70	5.09	5.92	N/A	ns
		XC6SLX45	4.63	4.98	5.83	7.26	ns
		XC6SLX45T	4.63	4.98	5.83	N/A	ns
		XC6SLX75	4.68	5.04	5.88	6.90	ns
		XC6SLX75T	4.68	5.04	5.88	N/A	ns
		XC6SLX100	4.72	5.07	5.92	7.77	ns
		XC6SLX100T	4.76	5.07	5.92	N/A	ns
		XC6SLX150	4.44	4.73	5.31	6.96	ns
		XC6SLX150T	4.44	4.73	5.31	N/A	ns
		XA6SLX4	5.07	N/A	6.18	N/A	ns
		XA6SLX9	5.07	N/A	6.18	N/A	ns
		XA6SLX16	5.22	N/A	5.77	N/A	ns
		XA6SLX25	5.01	N/A	5.80	N/A	ns
		XA6SLX25T	5.01	N/A	5.90	N/A	ns
		XA6SLX45	4.93	N/A	5.67	N/A	ns
		XA6SLX45T	4.93	N/A	5.67	N/A	ns
		XA6SLX75	4.94	N/A	5.70	N/A	ns
		XA6SLX75T	4.94	N/A	5.70	N/A	ns
		XA6SLX100	N/A	N/A	5.77	N/A	ns
		XQ6SLX75	N/A	N/A	5.70	6.90	ns
		XQ6SLX75T	4.94	N/A	5.70	N/A	ns
		XQ6SLX150	N/A	N/A	5.31	6.96	ns
		XQ6SLX150T	5.02	N/A	5.31	N/A	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. DCM and PLL output jitter are already included in the timing calculation.

Table 73: Global Clock Setup and Hold With DCM in Source-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVCMOS25 Standard. ⁽¹⁾							
T _{PSDCM0} / T _{PHDCM0}	No Delay Global Clock and IFF ⁽²⁾ with DCM in Source-Synchronous Mode	XC6SLX4	0.71/0.65	N/A	0.72/1.22	1.58/1.18	ns
		XC6SLX9	0.71/0.69	0.71/1.19	0.72/1.36	1.58/1.18	ns
		XC6SLX16	0.86/0.52	0.92/0.57	1.04/0.60	1.02/1.06	ns
		XC6SLX25	0.84/0.58	0.90/0.59	1.01/0.59	1.58/1.07	ns
		XC6SLX25T	0.84/0.58	0.90/0.59	1.01/0.59	N/A	ns
		XC6SLX45	0.85/0.70	0.90/0.76	0.98/0.79	1.34/1.34	ns
		XC6SLX45T	0.85/0.70	0.90/0.76	0.98/0.79	N/A	ns
		XC6SLX75	1.00/0.62	1.06/0.63	1.15/0.63	1.65/1.46	ns
		XC6SLX75T	1.00/0.71	1.06/0.72	1.15/0.72	N/A	ns
		XC6SLX100	0.81/0.68	0.81/0.69	0.94/0.69	1.42/2.07	ns
		XC6SLX100T	0.81/0.68	0.81/0.69	0.94/0.69	N/A	ns
		XC6SLX150	0.68/0.98	0.69/0.99	0.79/0.99	1.45/1.60	ns
		XC6SLX150T	0.68/0.98	0.69/0.99	0.79/0.99	N/A	ns
		XA6SLX4	0.81/0.74	N/A	0.72/1.36	N/A	ns
		XA6SLX9	0.81/0.74	N/A	0.72/1.36	N/A	ns
		XA6SLX16	1.01/0.56	N/A	1.04/0.60	N/A	ns
		XA6SLX25	0.94/0.76	N/A	1.06/0.77	N/A	ns
		XA6SLX25T	0.94/0.76	N/A	1.14/0.77	N/A	ns
		XA6SLX45	0.86/0.74	N/A	0.98/0.78	N/A	ns
		XA6SLX45T	0.86/0.74	N/A	0.98/0.78	N/A	ns
		XA6SLX75	1.02/0.71	N/A	1.15/0.72	N/A	ns
		XA6SLX75T	1.02/0.71	N/A	1.15/0.72	N/A	ns
		XA6SLX100	N/A	N/A	1.37/0.75	N/A	ns
		XQ6SLX75	N/A	N/A	1.15/0.72	1.65/1.46	ns
		XQ6SLX75T	1.02/0.71	N/A	1.15/0.72	N/A	ns
		XQ6SLX150	N/A	N/A	0.79/1.15	1.45/1.60	ns
		XQ6SLX150T	0.73/1.15	N/A	0.79/1.15	N/A	ns

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage. These measurements include DCM CLK0 jitter.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 75: Global Clock Setup and Hold With PLL in Source-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVC MOS25 Standard. ⁽¹⁾							
T _{PSPLL0} / T _{PHPLL0}	No Delay Global Clock and IFF ⁽²⁾ with PLL in Source-Synchronous Mode	XC6SLX4	0.47/1.08	N/A	0.47/1.60	1.15/1.68	ns
		XC6SLX9	0.47/1.08	0.47/1.35	0.47/1.60	1.15/1.68	ns
		XC6SLX16	0.37/0.75	0.37/0.82	0.51/0.94	0.57/1.31	ns
		XC6SLX25	0.69/1.06	0.69/1.06	0.69/1.06	1.86/1.67	ns
		XC6SLX25T	0.69/1.06	0.69/1.06	0.69/1.06	N/A	ns
		XC6SLX45	0.57/1.05	0.65/1.10	0.65/1.18	1.02/1.65	ns
		XC6SLX45T	0.57/1.06	0.65/1.10	0.65/1.18	N/A	ns
		XC6SLX75	0.86/1.04	0.87/1.04	0.90/1.04	1.34/1.55	ns
		XC6SLX75T	0.86/1.04	0.87/1.04	0.90/1.04	N/A	ns
		XC6SLX100	0.53/1.13	0.54/1.13	0.55/1.13	0.89/2.39	ns
		XC6SLX100T	0.53/1.13	0.54/1.13	0.55/1.13	N/A	ns
		XC6SLX150	0.50/1.31	0.51/1.31	0.52/1.31	1.02/1.72	ns
		XC6SLX150T	0.50/1.31	0.51/1.31	0.52/1.31	N/A	ns
		XA6SLX4	0.71/0.93	N/A	0.62/1.47	N/A	ns
		XA6SLX9	0.71/0.93	N/A	0.62/1.47	N/A	ns
		XA6SLX16	0.92/0.69	N/A	0.63/0.82	N/A	ns
		XA6SLX25	0.99/0.94	N/A	0.96/0.94	N/A	ns
		XA6SLX25T	0.99/0.94	N/A	1.04/0.94	N/A	ns
		XA6SLX45	0.63/1.02	N/A	0.72/1.05	N/A	ns
		XA6SLX45T	0.63/1.02	N/A	0.72/1.05	N/A	ns
		XA6SLX75	0.88/0.89	N/A	1.02/0.89	N/A	ns
		XA6SLX75T	0.88/0.89	N/A	1.02/0.89	N/A	ns
		XA6SLX100	N/A	N/A	1.25/0.96	N/A	ns
		XQ6SLX75	N/A	N/A	1.02/0.89	1.34/1.55	ns
		XQ6SLX75T	0.88/0.89	N/A	1.02/0.89	N/A	ns
		XQ6SLX150	N/A	N/A	0.63/1.19	1.02/1.72	ns
		XQ6SLX150T	0.60/1.19	N/A	0.63/1.19	N/A	ns

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage. These measurements include PLL CLKOUT0 jitter.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 81: Source-Synchronous Pin-to-Pin Setup/Hold and Clock-to-Out Using BUFIO2

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
Data Input Setup and Hold Times Relative to a Forwarded Clock Input Pin Using BUFIO2							
T _{PSCS} /T _{PHCS}	IFF setup/hold using BUFIO2 clock	XC6SLX4	0.57/0.94	N/A	0.95/1.12	0.27/1.56	ns
		XC6SLX9	0.40/0.95	0.50/0.96	0.60/1.12	0.27/1.56	ns
		XC6SLX16	0.48/0.74	0.55/0.75	0.69/0.83	1.27/1.31	ns
		XC6SLX25	0.28/1.02	0.28/1.12	0.28/1.24	0.15/1.78	ns
		XC6SLX25T	0.28/1.02	0.28/1.12	0.28/1.24	N/A	ns
		XC6SLX45	0.42/1.19	0.44/1.29	0.50/1.40	0.12/1.83	ns
		XC6SLX45T	0.42/1.19	0.44/1.29	0.50/1.40	N/A	ns
		XC6SLX75	0.38/1.48	0.38/1.63	0.38/1.84	0.05/2.78	ns
		XC6SLX75T	0.38/1.48	0.38/1.63	0.38/1.84	N/A	ns
		XC6SLX100	0.06/1.48	0.06/1.63	0.06/1.87	−0.03/2.72	ns
		XC6SLX100T	0.06/1.48	0.06/1.63	0.06/1.87	N/A	ns
		XC6SLX150	0.04/1.73	0.04/1.75	0.04/1.98	−0.08/3.07	ns
		XC6SLX150T	0.04/1.73	0.04/1.75	0.04/1.98	N/A	ns
		XA6SLX4	0.64/0.96	N/A	0.97/1.12	N/A	ns
		XA6SLX9	0.44/0.99	N/A	0.62/1.16	N/A	ns
		XA6SLX16	0.50/0.78	N/A	0.69/0.83	N/A	ns
		XA6SLX25	0.28/1.04	N/A	0.28/1.25	N/A	ns
		XA6SLX25T	0.28/1.04	N/A	0.28/1.25	N/A	ns
		XA6SLX45	0.43/1.21	N/A	0.50/1.40	N/A	ns
		XA6SLX45T	0.43/1.21	N/A	0.50/1.40	N/A	ns
		XA6SLX75	0.38/1.49	N/A	0.38/1.84	N/A	ns
		XA6SLX75T	0.38/1.49	N/A	0.38/1.84	N/A	ns
		XA6SLX100	N/A	N/A	1.01/1.63	N/A	ns
		XQ6SLX75	N/A	N/A	0.38/1.84	0.05/2.78	ns
		XQ6SLX75T	0.38/1.49	N/A	0.38/1.84	N/A	ns
		XQ6SLX150	N/A	N/A	0.04/1.98	−0.08/3.07	ns
		XQ6SLX150T	0.04/1.75	N/A	0.04/1.98	N/A	ns

Date	Version	Description of Revisions
06/14/10	1.5	In Table 2, added note 5 and added temperature range to V_{FS} and R_{FUSE}. Removed speed grade delineation, revised I_{RPD} description, and updated note 2 in Table 4. Added note 2 to Table 7. Added $DIFF_MOBILE_DDR$ to Table 8 and Table 10. Added note 4 to Table 15. Changed minimum DV_{PPIN} in Table 16. Updated $F_{GTPDRCLK}$ in Table 19. Increased maximum T_{LLSKEW} in Table 22. Updated descriptions and added data to Table 23. Removed note 1 and added new data to the Networking Applications section in Table 25. Updated Table 26 and Table 27 to the data in ISE v12.1 software with speed specification v1.08. In Table 28, added $DIFF_MOBILE_DDR$ and updated -4 speed grade data. Updated the maximum I/O pairs per bank in Table 33. Updated note 2 on Table 39. Revised the F_{MAX} in Table 44. In Table 47, updated description for $T_{SMCKCSO}$, revised values for T_{POR} and added Min value, added $T_{BPIICCK}$ and $T_{SPIICCK}$. Also in Table 47, added device dependencies to F_{SMCKCK} and F_{RBCKCK}. Updated and added data to Table 63 through Table 78, and Table 81. In Table 79, added data on the XC6SLX45-FG(G)676 and revised the XC6SLX45T and XC6SLX150T values. The following changes to this specification are addressed in the product change notice XC6SLX45-FG(G)676, MCB Performance and JTAG Revision Code for Spartan-6 LX16 and LX45 FPGAs. In Table 2, revised the V_{CCINT} to add the memory controller block extended performance specifications. In Table 25, changed the standard specifications and added extended performance specifications for the memory controller block and note 2. Added note 4 and updated values in Table 34.
06/24/10	1.6	Production release of XC6SLX45T (-2 and -3 speed grades), XC6SLX16 and XC6SLX45 (-3 speed grade) devices which includes changes to Table 26 and Table 27 (ISE v12.1 software with speed specification v1.08). Added the -3N speed grade, which designates Spartan-6 devices that do not support MCB functionality. This includes changes to Table 2 (note 2), Table 25 (note 4), and Switching Characteristics (Table 26). Updated Simultaneously Switching Outputs discussion. Added -3 speed grade values for T_{TAP} and F_{MINCAL} values in Table 39. In Table 40, updated T_{RPW} (-2 and -3 speed grade) values and F_{TOG} (-3 speed grade) values. In Table 48, updated T_{GIO} (-2 and -3 speed grade) values. Updated -3 values in spread spectrum section of Table 57.
07/16/10	1.7	Production release of specific devices listed in Table 26 and Table 27 using ISE v12.2 software with speed specification v1.11. Added note 4 advising designers of the patch which contains v1.11. Also updated the -1L speed specification to v1.04. Updated numerous -4 and -1L values. Added -4 T_{TAP} values and F_{MINCAL} to Table 39. Revised T_{CINCK}/T_{CKCIN} in Table 40. In Table 41, revised T_{SHCKO}. In Table 42, revised T_{REQ}. Added new -1L values to Table 47. Added and updated values in Table 79.
07/26/10	1.8	Production release of XC6SLX25, XC6SLX25T, XC6SLX100 and XC6SLX100T in the specific speed grades listed in Table 26 and Table 27 using ISE v12.2 software with speed specification v1.11. Added note 7 to Table 2 and moved V_{FS} and R_{FUSE} to a new Table 3. Added I_{HS} and note 4 to Table 4. Added note 1 to Table 28. Added and updated SSO limits per V_{CCO}/GND pairs in Table 34. Added note 3 to Table 47. In Table 54, removed -1L specifications for $CLKOUT_PER_JITT_DV1/2$ and revised $CLKIN_CLKFB_PHASE$ and $CLKOUT_PHASE_DLL$ values. Updated note 3 in both Table 56 and Table 57.
08/23/10	1.9	Updated values for $F_{GTPRANGE1}$, $F_{GTPRANGE2}$, and $F_{GPLLMIN}$ in Table 18. Revised -3 and -4 values in Table 21. Removed the -1L speed grade readback support restriction and note 3 in Table 47.
11/05/10	1.10	Production release of XC6SLX4 and XC6SLX9 in the specific speed grades listed in Table 26 and Table 27 using ISE v12.3 software with speed specification v1.12 for the -2 speed grade available in the 12.3 <i>Speed Files Patch</i>. Added note 3 advising designers of the patch which contains v1.12. In Table 2, added note 4. In Table 4, added note 2. In Table 10, added notes 2 and 3. In Table 44, added note 2. In Table 47, updated symbol for $T_{SMWCKCK}/T_{SMCKCKW}$, changed -1L values for $T_{USERCCLKH}$ and $T_{USERCCLKL}$, and added and revised the modes for F_{MCKCK} and F_{SMCKCK}. In Table 53, redefined and expanded description for $CLKIN_FREQ_DLL$ and rewrote note 3. Updated title of Table 58. Also in Table 78, revised T_{DCD_CLK} for XC6SLX150 and XC6SLX150T. Changed description of T_{PSFD}/T_{PHFD} in Table 71. For the -1L speed grade, updated data sheet to ISE 12.3 software with speed specification v1.05 which revised the values in the following tables: Table 25, Table 28, Table 35, Table 36, Table 37, Table 40 through Table 43, Table 48 through Table 56, Table 62 through Table 78, Table 80, and Table 81. Updated Notice of Disclaimer.